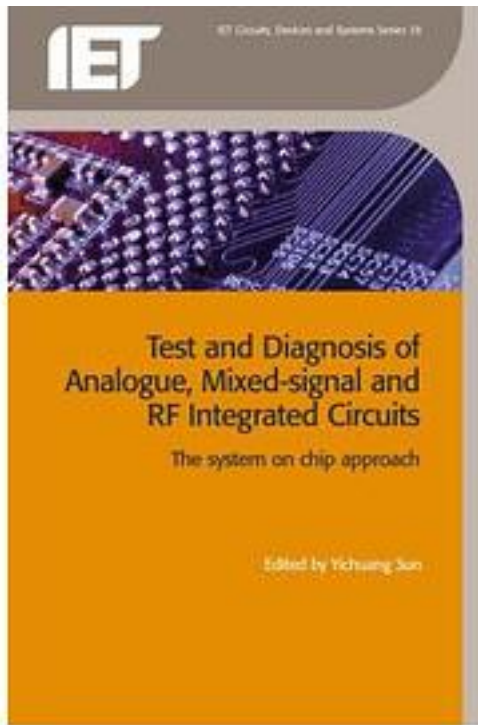


Test and Diagnosis of Analogue, Mixed-signal and RF Integrated Circuits



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